



VMDSEMI

VFPB010R095NA

Datasheet

General Description

The VMD VFPB010R095NA MOSFET is based on unique device design to achieve low $R_{DS(ON)}$, low gate charge, fast switching and excellent avalanche characteristics. The high V_{th} series is specially optimized for high systems with gate driving voltage greater than 10V.

Symbol

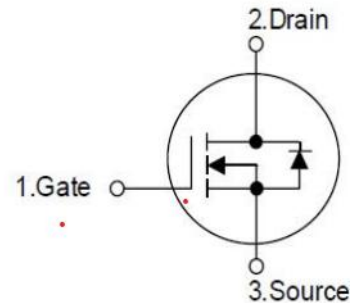


Figure 1 Symbol of VFPB010R095NA

Features

- Ultra Low $R_{DS(ON)_{max}} = 9.5m\Omega @ V_{GS} = 10V$.
- Extremely low switching loss
- Excellent stability and uniformity
- 100% UIS tested , 100% ΔV_{DS} Tested
- RoHS and Halogen-Free Compliant

Package Type

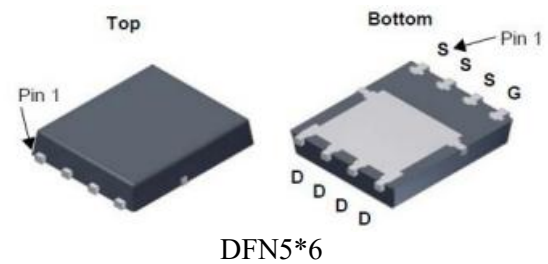


Figure 2 Package Type of VFPB010R095NA

Application

- Charger / Adapter
- Server/Telecom
- Synchronous Rectification
- High Frequency Switching

Ordering Information

| Product Name | Package |
|---------------|---------|
| VFPB010R095NA | PDFN5*6 |

Absolute Maximum Ratings

| Parameter | | Symbol | Rating | Unit |
|--|------------------------------------|----------------|------------|--------------------|
| Drain-Source Voltage | | V_{DSS} | 100 | V |
| Gate-Source Voltage | | V_{GSS} | ±20 | V |
| Continuous Drain Current | $T_C=25^{\circ}\text{C}$ (Note 5) | I_D | 60 | A |
| | $T_C=100^{\circ}\text{C}$ (Note 5) | | 38 | |
| Pulsed Drain Current (Note 3) | | I_{DM} | 240 | A |
| Power Dissipation, $T_C=25^{\circ}\text{C}$ (Note 2) | | P_D | 63 | W |
| Avalanche Energy, Single Pulse (Note 3,Note6) | | E_{AS} | 90 | mJ |
| Avalanche Current, Repetitive (Note 3,Note6) | | I_{AS} | 19 | A |
| Operating and Storage Temperature Range | | T_J, T_{STG} | -55 to 150 | $^{\circ}\text{C}$ |

Thermal Resistance

| Parameter | Symbol | Min | Typ | Max | Unit |
|---|-----------------|-----|-----|-----|-----------------------------|
| Thermal Resistance, Junction-to-Case | $R_{\theta JC}$ | | | 2.0 | $^{\circ}\text{C}/\text{W}$ |
| Thermal Resistance, Junction-to-Ambient(Note 1,Note4) | $R_{\theta JA}$ | | | 55 | $^{\circ}\text{C}/\text{W}$ |

Notes:

1. The value of $R_{\theta JC}$ is measured in a still air environment with $T_A = 25^{\circ}\text{C}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.
2. The power dissipation P_D is based on $T_{J(MAX)}=150^{\circ}\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heat sinking is used.
3. Single pulse width limited by junction temperature $T_{J(MAX)}=150^{\circ}\text{C}$.
4. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.
5. The maximum current rating is package limited.
6. The EAS data shows Max. rating. The test condition is $V_{DS}=50\text{V}, V_{GS}=10\text{V}, L=0.5\text{mH}$

Electrical Characteristics $T_J = 25\text{ }^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Test Conditions | Min | Typ | Max | Unit |
|--------------------------------------|--------------|---|-----|------|------|---------|
| Statistic Characteristics | | | | | | |
| Drain-Source Breakdown Voltage | BV_{DSS} | $V_{GS}=0V, I_D=250\mu A$ | 100 | | | V |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS}=80V, V_{GS}=0V$ | | | 1 | μA |
| Gate-Body Leakage Current | Forward | $I_{GSSF}, V_{GS}=20V, V_{DS}=0V$ | | | 100 | nA |
| | Reverse | $I_{GSSR}, V_{GS}=-20V, V_{DS}=0V$ | | | -100 | |
| Gate Threshold Voltage | $V_{GS(TH)}$ | $V_{DS}=V_{GS}, I_D=250\mu A$ | 1.2 | 1.8 | 2.6 | V |
| Static Drain-Source On-Resistance | $R_{DS(ON)}$ | $V_{GS}=10V, I_D=20A$ | | 8.2 | 9.5 | mΩ |
| Static Drain-Source On-Resistance | $R_{DS(ON)}$ | $V_{GS}=4.5V, I_D=10A$ | | 11.3 | 13.5 | mΩ |
| Forward Threshold Voltage | g_{fs} | $V_{DS}=5V, I_D=20A$ | | 13.5 | | S |
| Gate Resistance | R_G | F=1MHz, Open Drain | | 1.94 | | Ω |
| Dynamic Characteristics | | | | | | |
| Input Capacitance | C_{ISS} | $V_{DS}=50, V_{GS}=0V,$ $f=1MHz$ | | 2122 | | pF |
| Output Capacitance | C_{OSS} | | | 618 | | |
| Reverse Transfer Capacitance | C_{RSS} | | | 25 | | |
| Turn-on Delay Time | $t_{d(on)}$ | $V_{DD}=50V, I_D=20A,$ $R_G=3.0\Omega, V_{GS}=10V$ | | 17 | | ns |
| Rise Time | t_r | | | 4 | | |
| Turn-off Delay Time | $t_{d(off)}$ | | | 32 | | |
| Fall Time | t_f | | | 8 | | |
| Gate Charge Characteristics | | | | | | |
| Gate to Source Charge | Q_{gs} | $V_{DD}=50V, I_D=20A,$ $V_{GS}=10V$ | | 9 | | nC |
| Gate to Drain Charge | Q_{gd} | | | 10 | | |
| Gate Charge Total | Q_g | | | 41.8 | | |
| Reverse Diode Characteristics | | | | | | |
| Continuous Source Current | I_s | | | | 60 | A |
| Drain-Source Diode Forward Voltage | V_{SD} | $V_{GS}=0V, I_{SD}=20A$ | | 0.88 | 1.0 | V |
| Reverse Recovery Time | t_{rr} | $I_{SD}=20A,$ | | 50.5 | | ns |
| Reverse Recovery Charge | Q_{rr} | $dI_F/dt=100A/\mu s$ | | 71.5 | | nC |

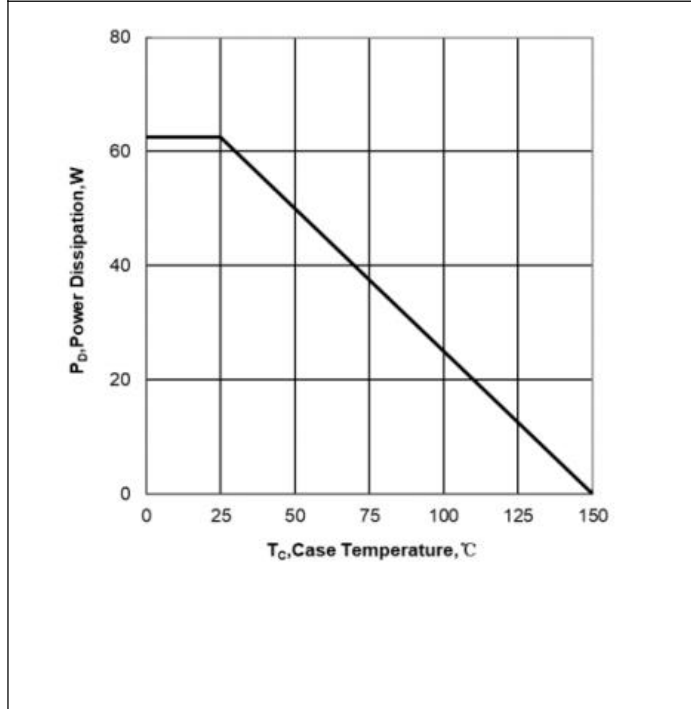
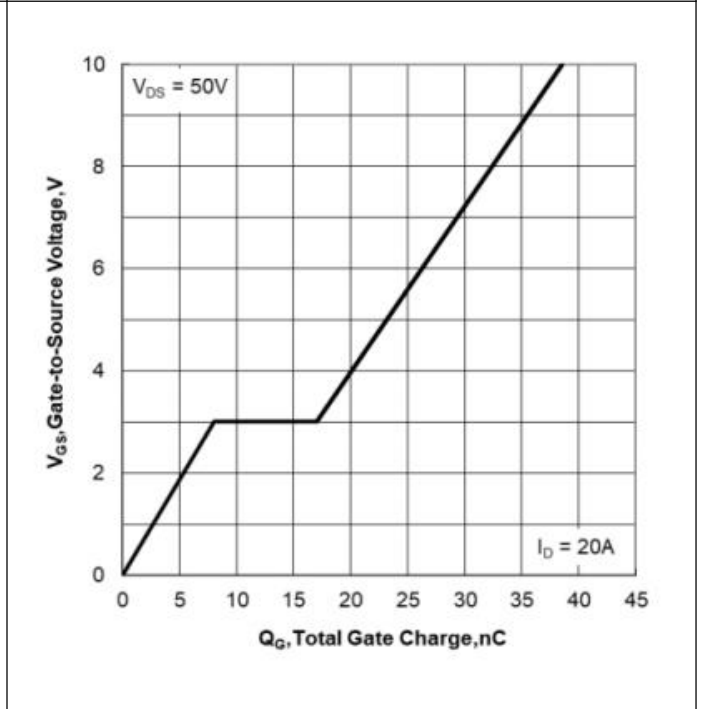
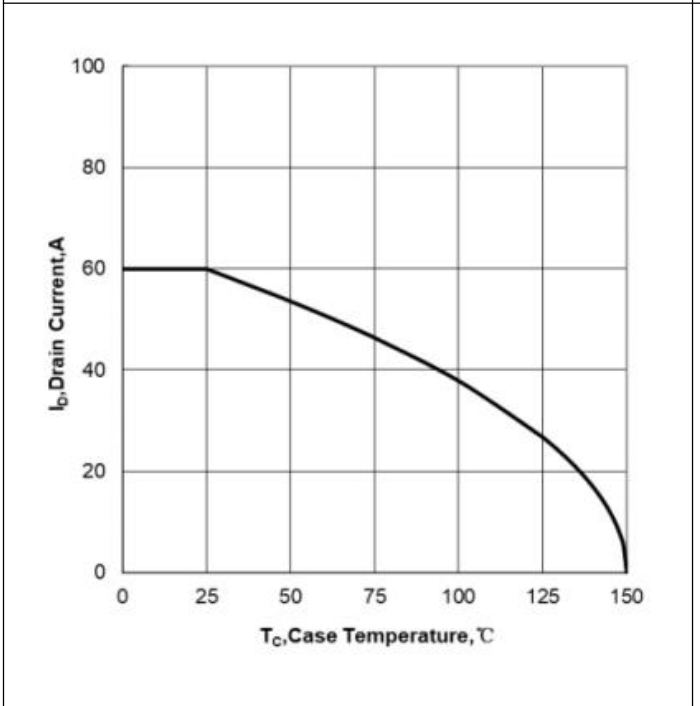
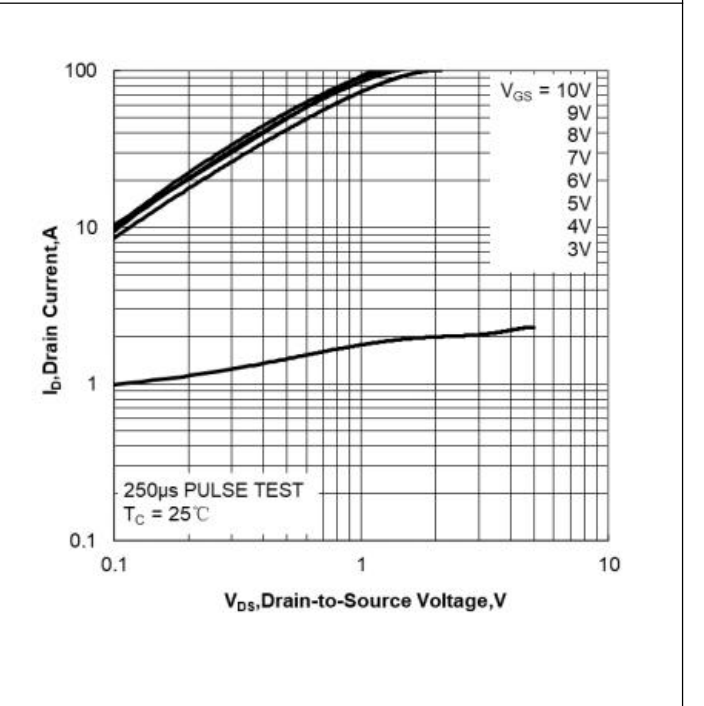
Typical Performance Characteristics
Figure 3: Maximum Power Dissipation vs Case Temperature

Figure 4: Gate Charge

Figure 5: Maximum Continuous Drain Current vs Case Temperature

Figure 6: Output Characteristics


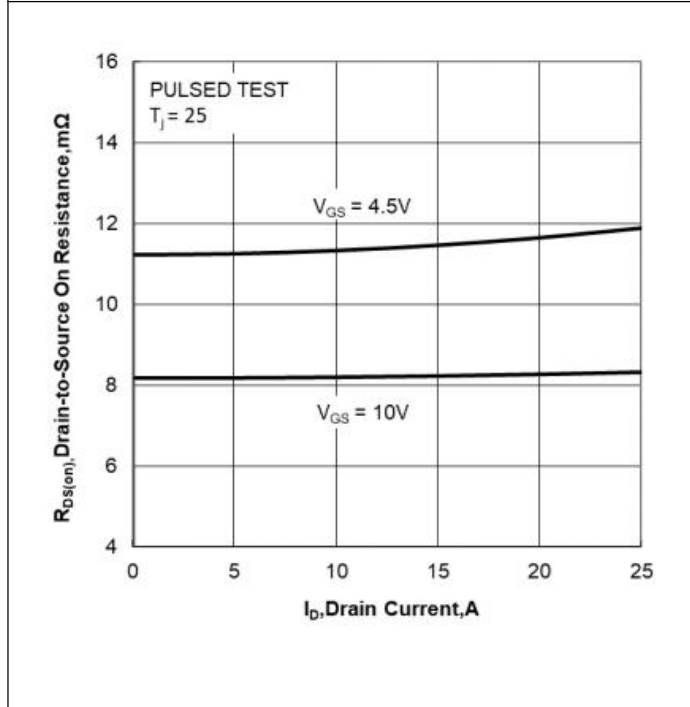
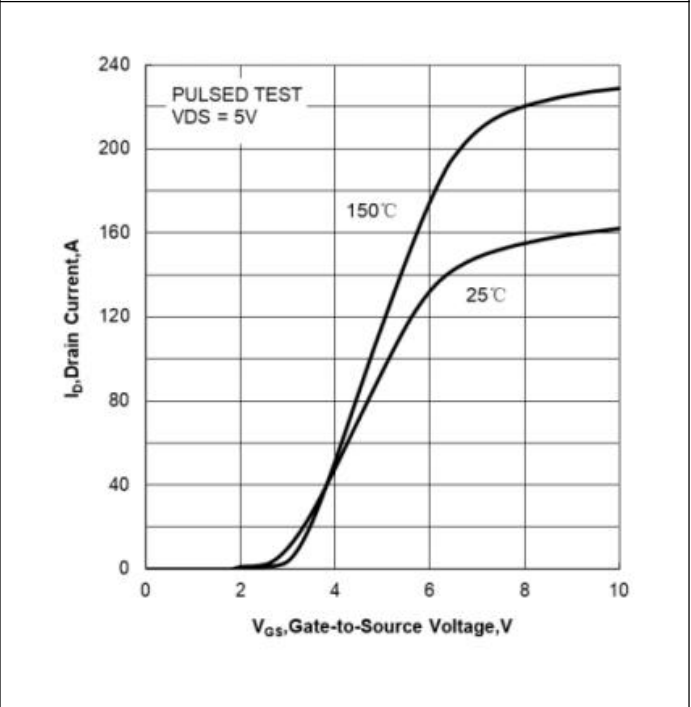
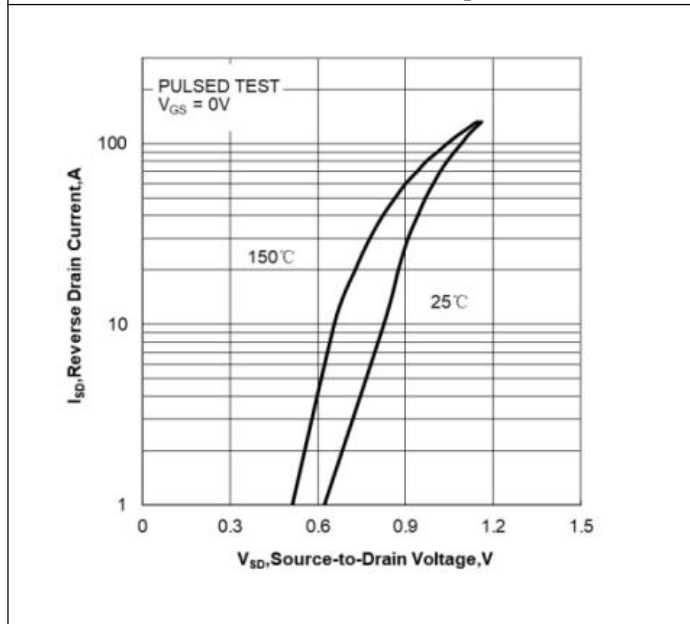
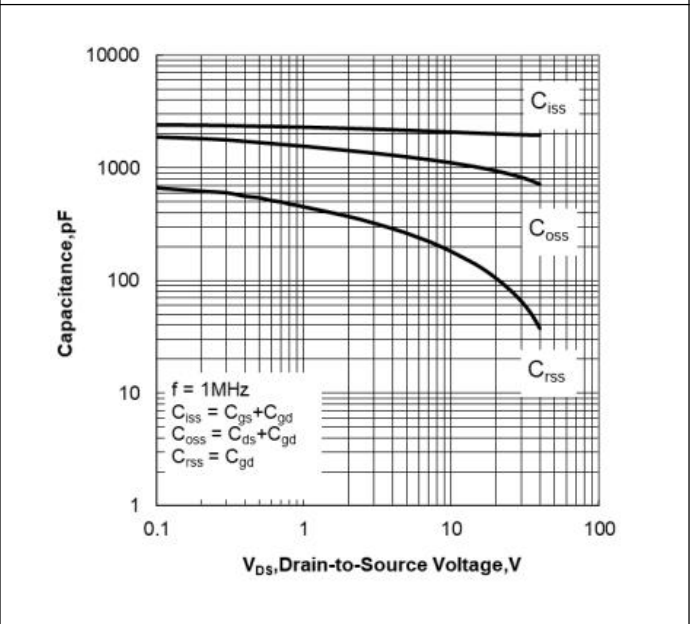
Figure 7: Drain-to-Source On Resistance vs Drain Current

Figure 8: Transfer Characteristics

Figure 9: Body Diode Forward Voltage vs Source Current and Temperature

Figure 10: Capacitance Characteristics


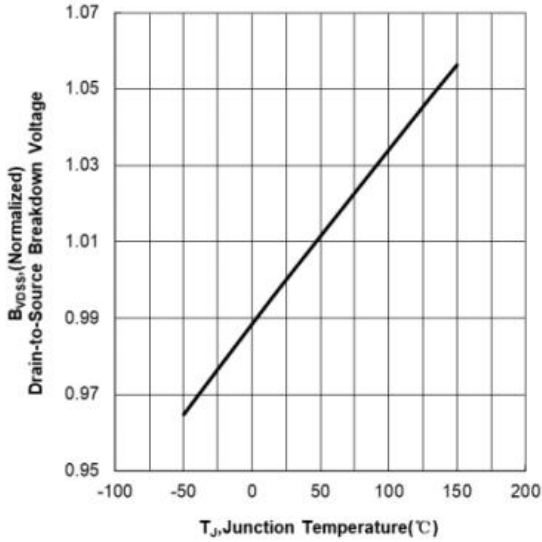
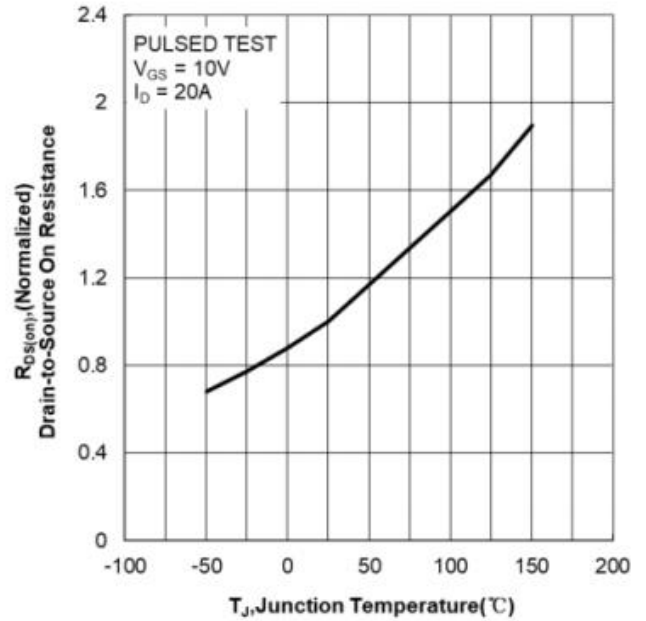
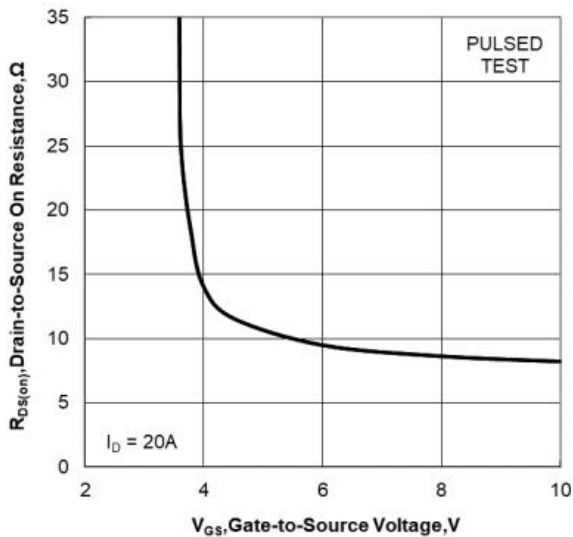
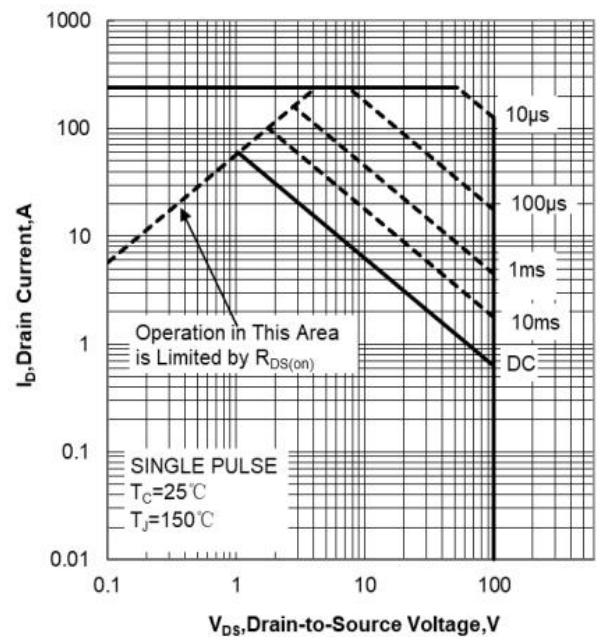
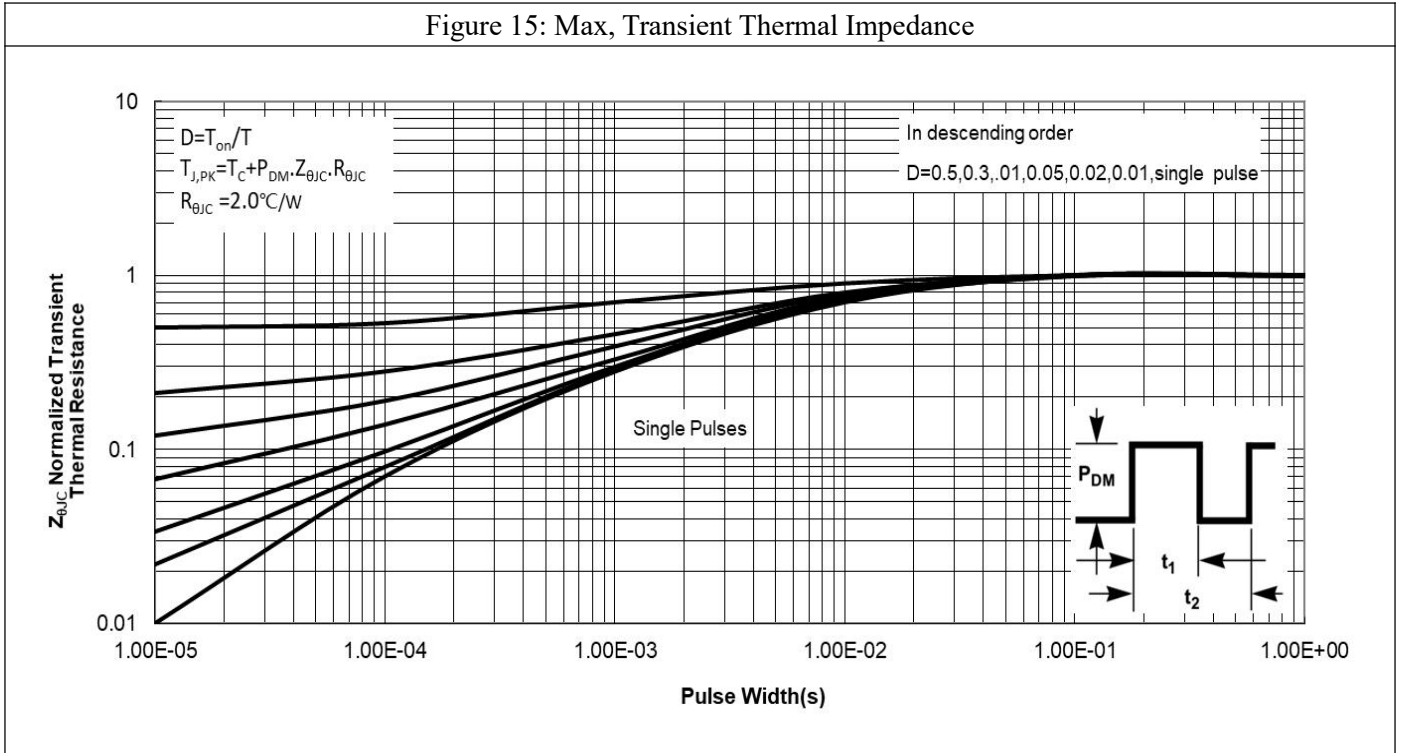
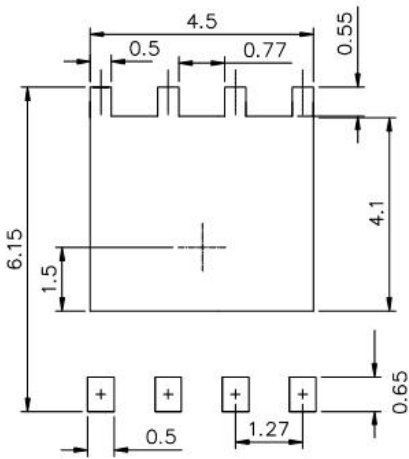
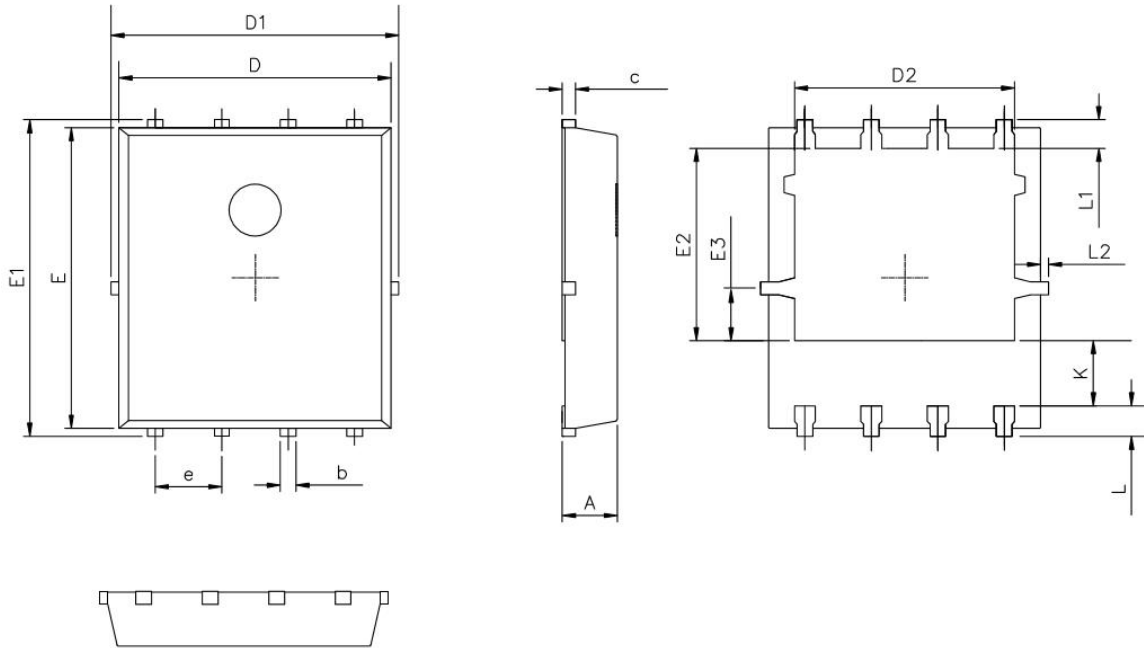
Figure 11: Normalized Breakdown Voltage vs Junction Temperature

Figure 12: Normalized On Resistance vs Junction Temperature

Figure 13: Drain-to-Source On Resistance vs Gate Voltage and Drain Current

Figure 14: Maximum Safe Operation Area


Figure 15: Max, Transient Thermal Impedance


Mechanical Dimensions (PDF5*6 Unit: mm)


| Symbol | Dimensions(mm) | | |
|--------|----------------|-------|-------|
| | Min. | Typ. | Max. |
| A | 0.9 | 1.0 | 1.10 |
| b | 0.25 | 0.35 | 0.50 |
| c | 0.10 | 0.20 | 0.30 |
| D | 4.80 | 5.00 | 5.30 |
| D1 | 4.90 | 5.10 | 5.50 |
| D2 | 3.92 | 4.02 | 4.20 |
| E | 5.65 | 5.75 | 5.85 |
| E1 | 5.90 | 6.05 | 6.20 |
| E2 | 3.325 | 3.525 | 3.775 |
| E3 | 0.80 | 0.90 | 1.00 |
| e | | 1.27 | |
| L | 0.40 | 0.55 | 0.70 |
| L1 | | 0.65 | |
| L2 | 0.00 | | 0.15 |
| K | 1.00 | 1.30 | 1.50 |

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